

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,058	DELINE, JONATHAN
Examiner	Art Unit
Khai M Nguyen	2617

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	420 419 418 550.1 563 567 458 557	12/27/2006	KN
370	365 343	12/27/2006	KN
		•	,
		-	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
see	attached	12/27/2006	KN	
	1			

(INCLUDING SE	ARCH STRATEGY	)
	DATE	EXMR
see attached	12/27/2006	KN
Vo Nguyen	12/22/2006	kn
Kostak Victor	12/22/2006	KN
		-